

Notice of References Cited	Application/Control No. 10/563,515		Applicant(s)/Patent Under Reexamination FUJII, TOSHIKI	
	Examiner BOBBY RAMDHANIE		Art Unit 1797	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,276,691	10-2007	Kodama et al.	250/309
	B	US-			
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	D	US-			
	E	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	U	JP2004-087174. Machine Translation Date 05/04/2009.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.